



**ALPHA & OMEGA**  
SEMICONDUCTOR



## AOD454

### N-Channel Enhancement Mode Field Effect Transistor

#### General Description

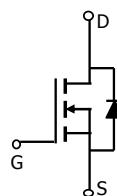
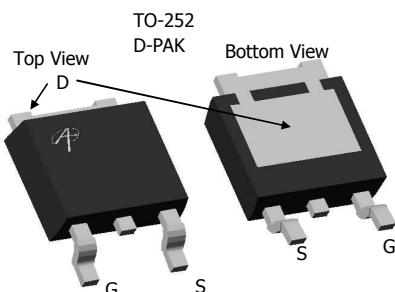
The AOD454 uses advanced trench technology and design to provide excellent  $R_{DS(ON)}$  with low gate charge. This device is suitable for use in PWM, load switching and general purpose applications.

- RoHS Compliant
- Halogen Free\*

#### Features

$V_{DS}$  (V) = 40V  
 $I_D$  = 12 A ( $V_{GS}$  = 10V)  
 $R_{DS(ON)} < 33 \text{ m}\Omega$  ( $V_{GS}$  = 10V)  
 $R_{DS(ON)} < 47 \text{ m}\Omega$  ( $V_{GS}$  = 4.5V)

**100% UIS Tested!**  
**100%  $R_g$  Tested!**



#### Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	$V_{DS}$	40	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Continuous Drain Current <sup>G</sup>	$I_D$	12	A
$T_C=100^\circ\text{C}$		10	
Pulsed Drain Current <sup>C</sup>	$I_{DM}$	30	
Avalanche Current <sup>C</sup>	$I_{AR}$	12	A
Repetitive avalanche energy $L=0.1\text{mH}$ <sup>C</sup>	$E_{AR}$	20	mJ
Power Dissipation <sup>B</sup>	$P_D$	50	W
$T_C=100^\circ\text{C}$		25	
Power Dissipation <sup>A</sup>	$P_{DSM}$	2	W
$T_A=70^\circ\text{C}$		1.3	
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 175	°C

#### Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup>	$R_{\theta JA}$	17.4	30	°C/W
Maximum Junction-to-Ambient <sup>A</sup>		50	60	°C/W
Maximum Junction-to-Case <sup>B</sup>	$R_{\theta JC}$	2.3	3	°C/W

**Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$I_D=10\text{mA}, V_{GS}=0\text{V}$	40			V
$I_{\text{DSS}}$	Zero Gate Voltage Drain Current	$V_{DS}=32\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$		1	5	$\mu\text{A}$
$I_{GSS}$	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm20\text{V}$			$\pm100$	nA
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	1.8	2.3	3	V
$I_{D(\text{ON})}$	On state drain current	$V_{GS}=10\text{V}, V_{DS}=5\text{V}$	30			A
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=12\text{A}$		25	33	$\text{m}\Omega$
		$T_J=125^\circ\text{C}$		39	52	$\text{m}\Omega$
		$V_{GS}=4.5\text{V}, I_D=6\text{A}$		34	47	$\text{m}\Omega$
$g_{FS}$	Forward Transconductance	$V_{DS}=5\text{V}, I_D=12\text{A}$		25		S
$V_{SD}$	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.76	1	V
$I_S$	Maximum Body-Diode Continuous Current				12	A
<b>DYNAMIC PARAMETERS</b>						
$C_{iss}$	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=20\text{V}, f=1\text{MHz}$		404	500	pF
$C_{oss}$	Output Capacitance			95	150	pF
$C_{rss}$	Reverse Transfer Capacitance			37	60	pF
$R_g$	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$		2.7		$\Omega$
<b>SWITCHING PARAMETERS</b>						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=10\text{V}, V_{DS}=20\text{V}, I_D=12\text{A}$		9.2		nC
$Q_g(4.5\text{V})$	Total Gate Charge			4.5		nC
$Q_{gs}$	Gate Source Charge			1.6		nC
$Q_{gd}$	Gate Drain Charge			2.6		nC
$t_{D(\text{on})}$	Turn-On DelayTime	$V_{GS}=10\text{V}, V_{DS}=20\text{V}, R_L=1.7\Omega, R_{\text{GEN}}=3\Omega$		3.5		ns
$t_r$	Turn-On Rise Time			6		ns
$t_{D(\text{off})}$	Turn-Off DelayTime			13.2		ns
$t_f$	Turn-Off Fall Time			3.5		ns
$t_{rr}$	Body Diode Reverse Recovery Time	$I_F=12\text{A}, dI/dt=100\text{A}/\mu\text{s}$		22.9		ns
$Q_{rr}$	Body Diode Reverse Recovery Charge	$I_F=12\text{A}, dI/dt=100\text{A}/\mu\text{s}$		18.3		nC

A: The value of  $R_{\theta JA}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The Power dissipation  $P_{DSM}$  is based on  $R_{\theta JA}$  and the maximum allowed junction temperature of 150°C. The value in any given application depends on the user's specific board design, and the maximum temperature of 175°C may be used if the PCB allows it.

B. The power dissipation  $P_D$  is based on  $T_{J(\text{MAX})}=175^\circ\text{C}$ , using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C: Repetitive rating, pulse width limited by junction temperature  $T_{J(\text{MAX})}=175^\circ\text{C}$ .

D. The  $R_{\theta JA}$  is the sum of the thermal impedance from junction to case  $R_{\theta JC}$  and case to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300  $\mu\text{s}$  pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of  $T_{J(\text{MAX})}=175^\circ\text{C}$ .

G. The maximum current rating is limited by bond-wires.

H. These tests are performed with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The SOA curve provides a single pulse rating.

\*This device is guaranteed green after data code 8X11 (Sep 1<sup>ST</sup> 2008).

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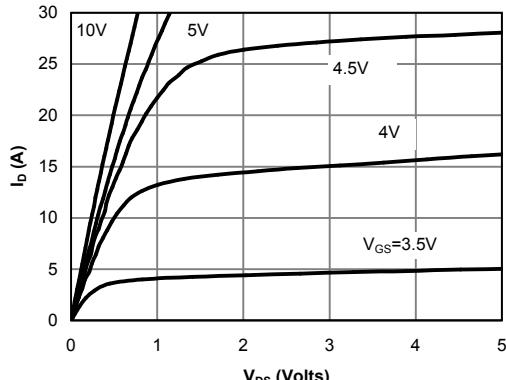
**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

Fig 1: On-Region Characteristics

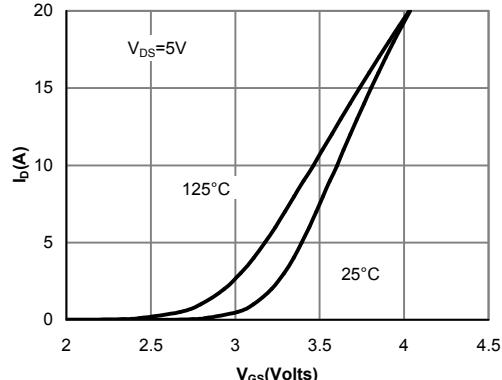


Figure 2: Transfer Characteristics

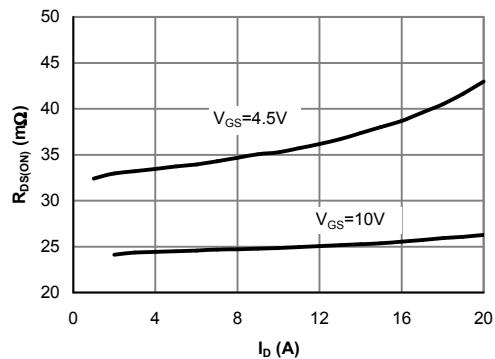


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

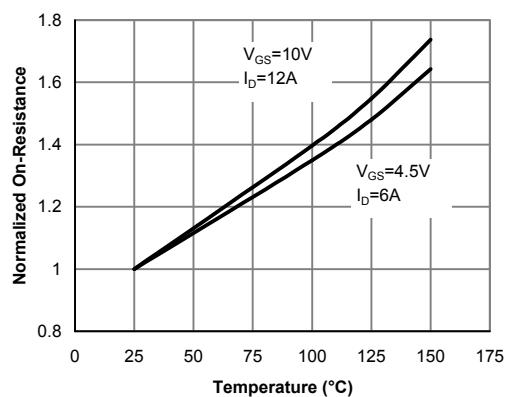


Figure 4: On-Resistance vs. Junction Temperature

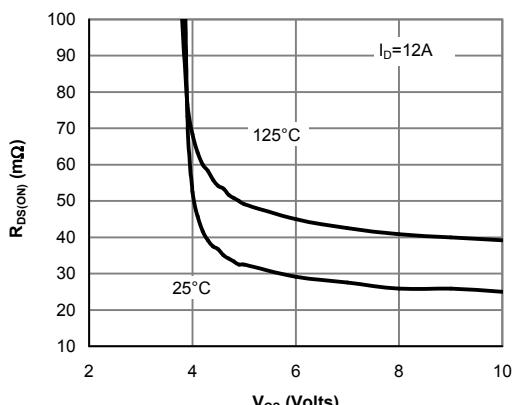


Figure 5: On-Resistance vs. Gate-Source Voltage

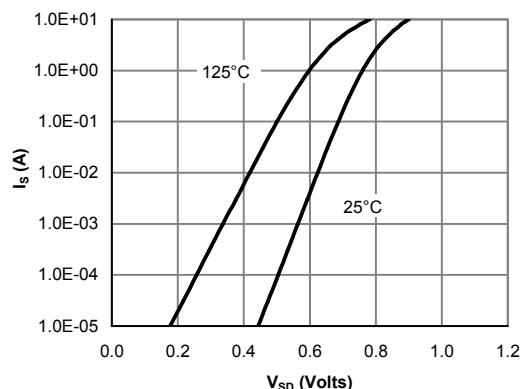


Figure 6: Body-Diode Characteristics

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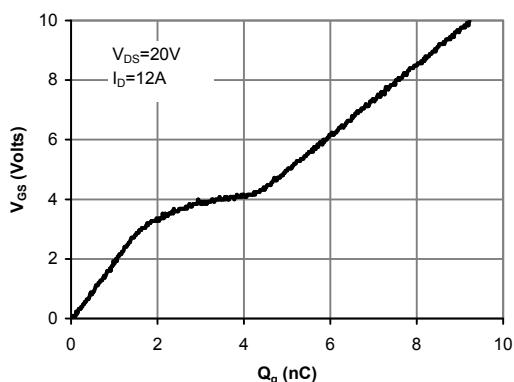
**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**


Figure 7: Gate-Charge Characteristics

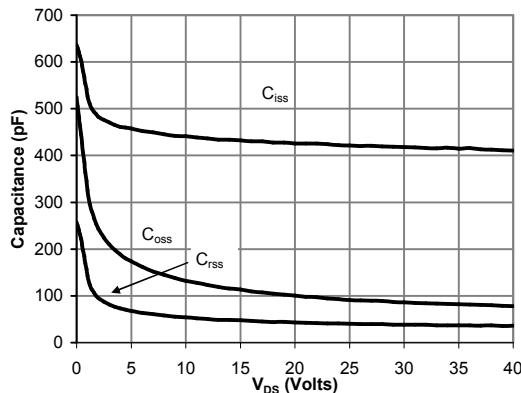


Figure 8: Capacitance Characteristics

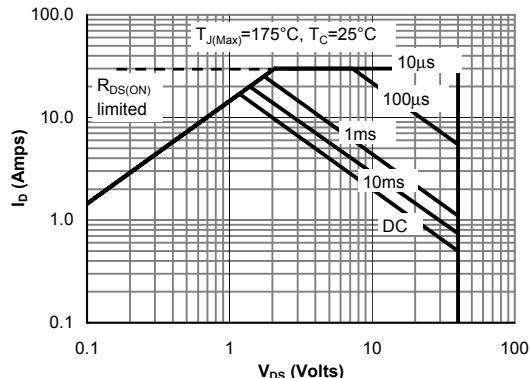


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

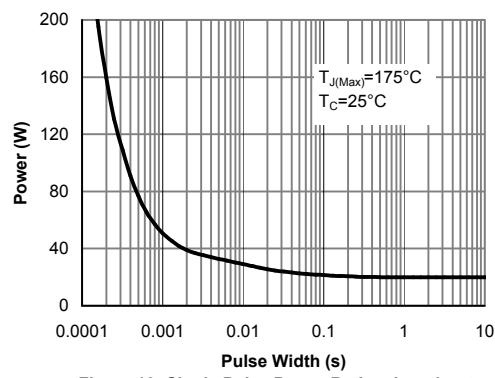


Figure 10: Single Pulse Power Rating Junction-to-Case (Note F)

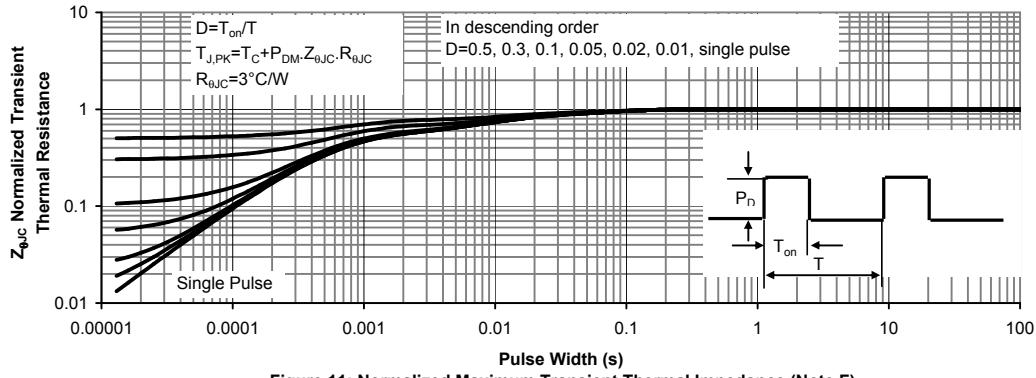


Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

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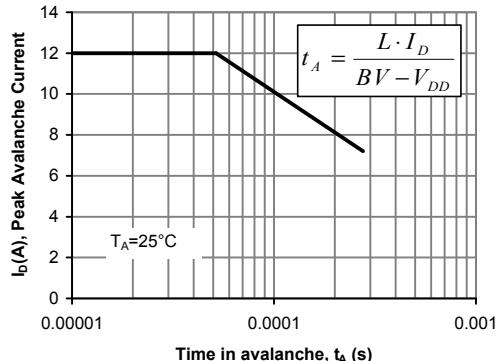
**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**


Figure 12: Single Pulse Avalanche capability  
Note B

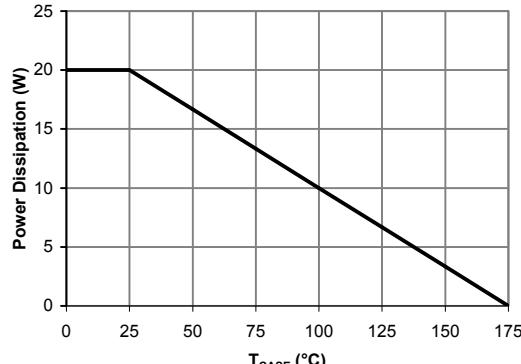


Figure 13: Power De-rating (Note B)

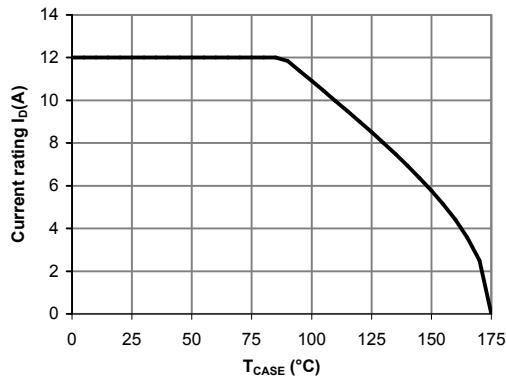


Figure 14: Current De-rating (Note B)

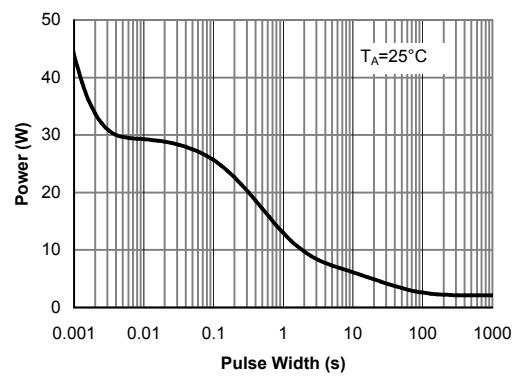


Figure 15: Single Pulse Power Rating Junction-to-Ambient (Note H)

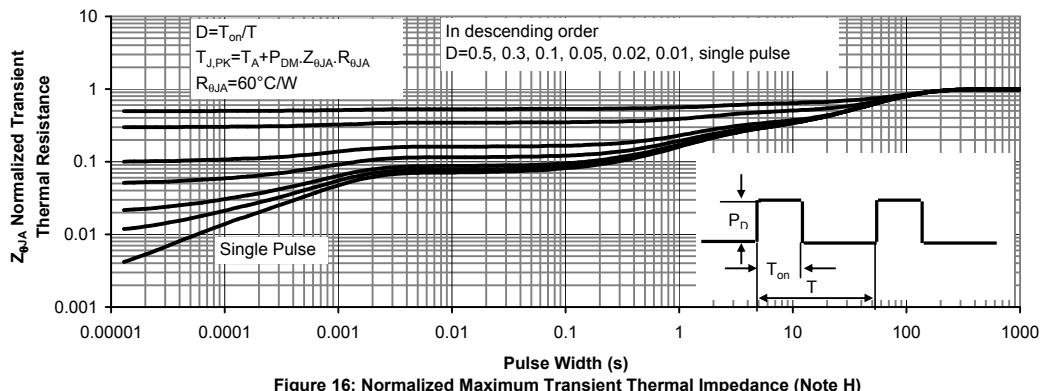
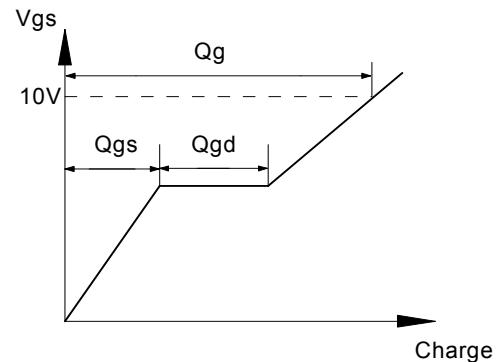
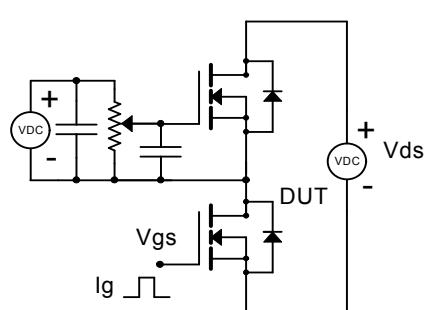
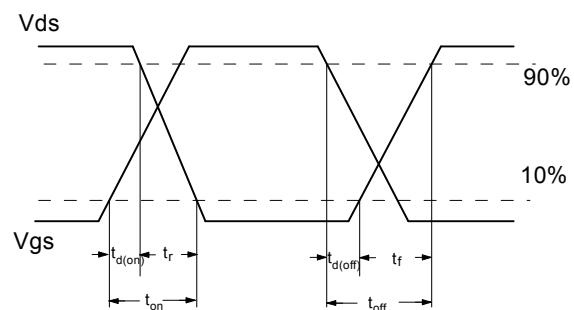
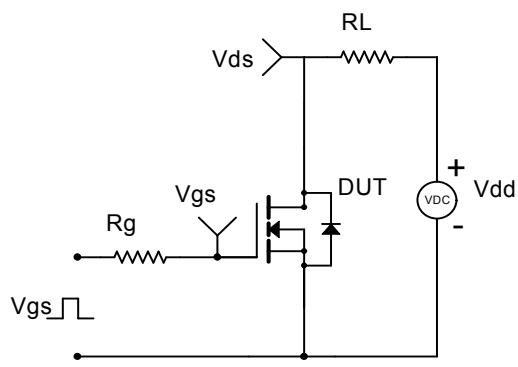


Figure 16: Normalized Maximum Transient Thermal Impedance (Note H)

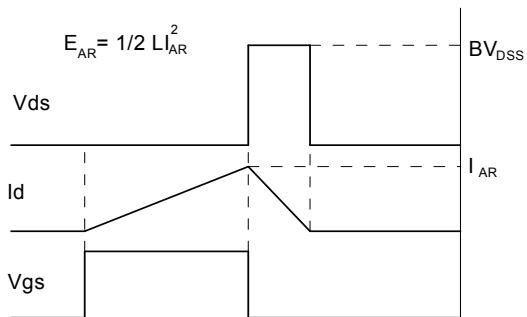
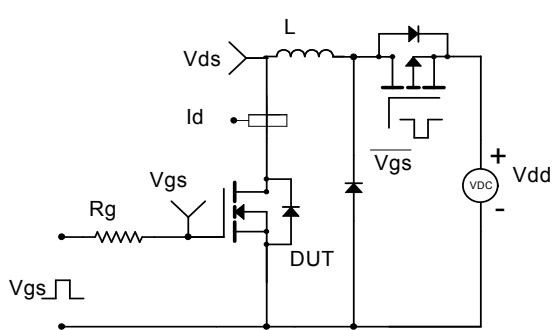
## Gate Charge Test Circuit &amp; Waveform



## Resistive Switching Test Circuit &amp; Waveforms



## Unclamped Inductive Switching (UIS) Test Circuit &amp; Waveforms



## Diode Recovery Test Circuit &amp; Waveforms

